## VII. X RAY DIFFRACTION STUDIES

All runs in the reaction product studies were analyzed by the Debye-Sherrer or powder diffraction method. The samples were ground between two polished tungsten carbide surfaces and loaded in a 0.5 mm glass capillary. Diffraction patterns were obtained on a 143 mm Debye-Sherrer camera with a General Electric CA-7 copper X ray tube using 1.5 to 2 hours exposure. The best films were read on a General Electric Fluoroline illuminator and d values were calculated on the IBM 7040 computer.

The LaSb2 type patterns were indexed by comparing them to the NdSb2 indexing given by Wang (25). Several additional lines were indexed by comparing observed d values with calculated d<sub>hkl</sub> values using the structure factors given for NdSb2 by Wang and Steinfink (1). The structure factors allowed the selection of the proper d values for the LaSb2 type structure from the list of possible d values calculated from the lattice parameters and Miller indicies. Lattice parameters were calculated by a least squares fit of the observed d values and the assigned Miller indicies. The X ray diffraction data and Miller indicies of the LaSb2 type compounds are given in Table10 in the Appendix.

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